

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SJ/T 11630-2016

Solar-wafer geometry test method

太阳能电池用硅片几何尺寸测试方法

(English Translation)

Issued on: April 5, 2016

Implemented on: September 1, 2016

Issued by: Ministry of Industry and Information Technology

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What this standard covers

This standard specifies the test method for the geometry of silicon wafers for solar cells. The geometric dimension parameters include side length, diagonal, adjacent side perpendicularity, chamfer width and chamfer angle. The main contents include normative references, terms and definitions, method principles, interference factors, equipment, sample requirements, test environment, test procedures, precision and test reports.

Document data

Chinese classification (CCS): H21.

Estimated length of the Chinese original: 8,860 words.